PCN Number:	20211101000.1						PCN Date: November 03, 2021					
Title: Qualify HNT as an additional Assembly site for select devices												
Customer Contact: PCN Manager Dept: Quality Services												
Proposed 1 st Ship Dat		e: Feb 05, 2022			Estimated Sample Availability:				ided upon Request			
Change Type:	Change Type:											
Assembly Site		Design							Wafer Bump Site			
Assembly Process Assembly Materials		Data Sh						╡┼	Wafer Bump Material Wafer Bump Process			
Assembly Materials						iber change			Wafer Fab Site			
Packing/Shipping/I			Test Proc						Wafer Fab Materials			
				1000000				Ī	Wafer Fab Process			
				PCN	Deta	ils						
Description of Chang	e:											
for select devices listed	Texas Instruments Incorporated is announcing the qualification of HNT as Additional Assembly Site for select devices listed in the "Product Affected" Section. Current assembly sites and Material differences are as follows.											
-	A	-	·	te Origir		embly Co		itry	/ Coue			
TI Melaka			CU6		_	MYS				Melaka		
Hana Semiconducto	or	H	INT			TH	4			Ayutthaya		
Material Differences:			TTE			Liana (
Mount Compound				TIEM Hana S 223179			Semiconductor 400194					
Mold Compound				97131			450419					
	1											
Reason for Change:												
Continuity of Supply												
Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):												
None												
Impact on Environmental Ratings												
Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.												
RoHS			EAC			Green Sta		us		IEC 62474		
🛛 No Change	\triangleright	🛛 No Ch	ange	e	\bowtie	No Change	2			No Change		
Changes to product identification resulting from this PCN:												
Assembly Site												
TI Melaka				Origin (2		ASO: CU6		_				
Hana Semiconductor	Ass	sembly S	Site	Origin (2	2L)	ASO: HNT	-					
Sample product shipping label (not actual product label)												

MADE IN: Malaysia 20: 20: MSL 2 /260C/1 YEAR SEAL I MSL 1 /235C/UNLIM 03/29/ 0PT: ITEM: 39 LBL: 5A (L)T0:175	(04) 060 060 060	(1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY (1T) 7523483SI2 (P) (2P) REV: (V) 0033317 (20L) CSO-SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS
Product Affected		
TPL5010DDCR	TPL5010DDCT	

Qualification Report

Automotive New Product Qualification Summary (As per AEC-Q100 and JEDEC Guidelines) Approve Date 21-Oct-2021

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Spec	Min Lot Qty	SS/Lot	Test Name / Condition	Duration	Qual Device: TPL5010QDDCRQ1
	TEST GROUP A – ACCELERATED ENVIRONMENT STRESS TESTS						
PC	A1	J-STD-020 JESD22-A113	3	77	Auto Preconditioning Level 1 - 260C		3/597/0
AC	A3	JEDEC JESD22-A102	3	77	Autoclave, 121C	96 Hours	3/231/0
тс	A4	JEDEC JESD22-A104 & Appendix 3	3	77	Temperature Cycle, Grade 1, -65/150C	500 Cycles	3/231/0
TC- WBP	A4	MIL-STD883 Method 2011	1	60	Auto Post TC Bond Pull	Wires	3/90/0
HTSL	A6	JEDEC JESD22-A103	1	45	High Temperature Storage Life, 170C	420 Hours	3/135/0
				TEST GRC	OUP C – PACKAGE ASSEMBLY INTEGRIT	Y TESTS	
WBS	C1	AEC Q100-001	3	30	Wire Bond Shear (Cpk>1.67)	Bonds	3/90/0
WBP	C2	MIL-STD883 Method 2011	3	30	Wire Bond Pull (Cpk>1.67)	Wires	3/90/0
SD	C3	JEDEC JESD22-B102	1	15	Surface Mount Solderability (Pb)	>95% Lead Coverage, 155C Dry Bake	3/45/0
SD	C3	JEDEC JESD22-B102	1	15	Surface Mount Solderability (Pb-Free)	>95% Lead Coverage, 155C Dry Bake	3/45/0
PD	C4	JEDEC JESD22-B100 and B108	3	10	Auto Physical Dimensions	(Cpk>1.67)	3/30/0
LI	C6	JEDEC JESD22-B105	1	50	Lead Integrity	# of leads to destruction	3/45/0
	TEST GROUP D – DIE FABRICATION RELIABILITY TESTS						
EM	D1	JESD61	-	-	Electromigration	-	Completed Per Process Technology Requirements
TDDB	D2	JESD35	-	-	Time Dependent Dielectric Breakdown	-	Completed Per Process Technology Requirements
HCI	D3	JESD60 & 28	-	-	Hot Injection Carrier	-	Completed Per Process Technology Requirements

Туре	#	Test Spec	Min Lot Qty	SS/Lot	Test Name / Condition	Duration	Qual Device: TPL5010QDDCRQ1
NBTI	D4	-	-	-	Negative Bias Temperature Instability -		Completed Per Process Technology Requirements
SM	D5	-	-	-	Stress Migration	-	Completed Per Process Technology Requirements
					OTHER QUALIFICATION TESTS		
MQ	-	Per Automotive requirements	3	1	Manufacturability (Auto Assembly)	-	3/PASS
DSS		MIL-STD-883 Method 2019	3	10	Die Shear	Die	3/30/0
LFA	-	-	3	15	Lead Finish Adhesion	Leads, 5 parts minimum	3/45/0
LP	-	-	3	24	Lead Pull	Leads, 8 parts minimum	3/72/0
XR	-	-	3	5	X-Ray	Top side only	3/15/0
YLD	-	Per datasheet specifications	3	All	FTY and Bin Summary	-	3/PASS
MSL	-	-	3	12	Moisture Sensitivity	Level 1 – 260C	3/36/0

- Qual Device TPL5010QDDCRQ1 is qualified at LEVEL1-260C

A1 (PC): Preconditioning: Performed for THB, Biased HAST, AC, uHAST, TC & PTC samples, as applicable.

Ambient Operating Temperature by Automotive Grade Level: Grade 0 (or E): -40°C to +150°C Grade 1 (or Q): -40°C to +125°C Grade 2 (or T): -40°C to +105°C Grade 3 (or I) : -40°C to +85°C

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status: Qualified Pb-Free (SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
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